

# Mini-Minimax Uncertainty of Emulators

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Intro

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Accuracy

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Theory

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Bounds

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CAM1

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Bounds2

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CAM2

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Extensions

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Conclusions

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# Emulators, Surrogate functions, Metamodels

Try to approximate a function  $f$  from few samples when evaluating  $f$  expensive: computational cost or experiment.

## Emulators are essentially interpolators/smoothers

- Kriging
- Gaussian process models (GP)
- Polynomial Chaos Expansions
- Multivariate Adaptive Regression Splines (MARS)
- Projection Pursuit Regression
- Neural networks

# Noiseless non-parametric function estimation

Estimate  $f$  on domain  $\text{dom}(f)$  from  $\{f(x_1), \dots, f(x_n)\}$

- $f$  infinite-dimensional.
- $\text{dom}(f)$  typically high-dimensional.
- Observe only  $f|_X$ , where  $X = \{x_1, \dots, x_n\}$ . No noise.
- Estimating  $f$  is grossly underdetermined problem (worse with noise).
- Usual context: question that requires knowing  $f(x)$  for  $x \notin X$

## Common context

### Part of larger problem in uncertainty quantification (UQ)

- Real-world phenomenon
- Physics description of phenomenon
- Theoretical simplification/approximation of the physics
- Numerical solution of the approximation  $f$
- Emulation of the numerical solution of the approximation  $\hat{f}$
- Calibration to noisy data
- “Inference”

## HEB: *H*igh dimensional domain, *E*xpensive, *B*lack-box

- Climate models (Covey et al. 2011: 21–28-dimensional domain 1154 simulations, Kriging and MARS)
- Car crashes (Aspenberg et al. 2012: 15-dimensional domain; 55 simulations; polynomial response surfaces, NN)
- Chemical reactions (Holena et al. 2011: 20–30-dimensional domain, boosted surrogate models; Shorter et al., 1999: 46-dimensional domain)
- Aircraft design (Srivastava et al. 2004: 25-dimensional domain, 500 simulations, response surfaces and Kriging; Koch et al. 1999: 22-dimensional domain, minutes per run, response surfaces and Kriging; Booker et al. 1999: 31-dimensional domain, minutes to days per run, Kriging)
- Electric circuits (Bates et al. 1996: 60-dimensional domain; 216 simulations; Kriging)

## Emulator Accuracy Matters

- High-consequence decisions are made on the basis of emulators.
- How accurate are they in practice?
- How can the accuracy be estimated reliably, measured, or bounded?
- How many training data are needed to ensure that an emulator (the best possible) is accurate?

## Common strategies to estimate accuracy

### Bayesian Emulators (GP, Kriging, ...)

- Use the posterior distribution (Tebaldi & Smith 2005)
- Posterior depends on prior and likelihood, but inputs are generally fixed parameters, not random.

### Others

- Using holdout data (Fang et al. 2006)
- Relevant only if the error at the held-out data is representative of the error everywhere.  
Data not usually IID; values of  $f$  not IID.

Required conditions generally unverifiable or known to be false.

## So, what to do?

- Standard methods can be misleading when the assumptions don't hold—and usually no reason for the assumptions to hold.
- Is there a more rigorous way to evaluate the accuracy?
- Is there a way that relies only on the observed data?

## Constraints are mandatory

- Uncertainty estimates are driven by *assumptions* about  $f$ .
- Without constraints on  $f$ , no reliable way to extrapolate to values of  $f$  at unobserved inputs: completely uncertain.
- Stronger assumptions  $\rightarrow$  smaller uncertainties.
- What's the most optimistic assumption the data justify?

## (Best) Lipschitz constant

Given a metric  $d$  on  $\text{dom}(g)$ , *best Lipschitz constant*  $K$  for  $g$  is

$$K(g) \equiv \sup \left\{ \frac{g(v) - g(w)}{d(v, w)} : v, w \in \text{dom}(g) \text{ and } v \neq w \right\}. \quad (1)$$

If  $f \notin \mathcal{C}(\text{dom}(f))$ , then  $K(f) \equiv \infty$ .

## What's the problem?

- If we knew  $f$ , we could emulate it perfectly—by  $f$ .
- Require emulator  $\hat{f}$  to be computable from the data, without relying on any other information about  $f$ .
- If we knew  $K(f)$ , could guarantee *some* level of accuracy for  $\hat{f}$ .
- All else equal, the larger  $K(f)$  is, the harder to guarantee that  $\hat{f}$  is accurate.

## How bad *must* the uncertainty be?

- Data  $f|_{\mathcal{X}}$  impose a lower bound on  $K(f)$  (but no upper bound): Data *require* some lack of regularity.
- Is there any  $\hat{f}$  guaranteed to be close to  $f$ —no matter what  $f$  is—provided  $f$  agrees with  $f|_{\mathcal{X}}$  and is not less regular than the data require?

## Minimax formulation: Information-Based Complexity (IBC)

- *potential error at  $w$* : minimax error of emulators  $\hat{f}$  over the set  $\mathcal{F}$  of functions  $g$  that agree with data & have  $K(g)$  constant no greater than the lower bound, at  $w \in \text{dom}(f)$ .
- *maximum potential error*: sup of potential error over  $w \in \text{dom}(f)$ .
- For known  $K$ , finding potential error is standard IBC problem.
- But  $K(f)$  is unknown: Bound potential error using a lower bound for  $K(f)$  computed from data.

## Sketch of results

- Lower bound on additional observations possibly necessary to estimate  $f$  w/i  $\epsilon$ .
- Application to Community Atmosphere Model (CAM): required  $n$  could be ginormous.
- Lower bounds on the max potential error for approximating  $f$  from a fixed set of observations: empirical, and as a fraction of the unknown  $K$ .
- Conditions under which a constant emulator has smaller maximum potential error than best emulator trained on the actual observations. Conditions hold for the CAM simulations.
- Sampling to estimate quantiles and mean of the potential error over  $\text{dom}(f)$ . For CAM, moderate quantiles are a large fraction of maximum.

## Notation

$f$ : fixed unknown real-valued function on  $[0, 1]^p$

$\mathcal{C}[0, 1]^p$ : real-valued continuous functions on  $[0, 1]^p$

$\text{dom}(g)$ : domain of the function  $g$

$g|_D$ : restriction of  $g$  to  $D \subset \text{dom}(g)$

$f|_X$ :  $f$  at the  $n$  points in  $X$ , the data

$\hat{f}$ : emulator based on  $f|_X$ , but no other information about  $f$

$\|h\|_\infty \equiv \sup_{w \in \text{dom}(h)} |h(w)|$

$d$ : a metric on  $\text{dom}(g)$

$K(g)$ : best Lipschitz constant for  $f$  (using metric  $d$ )

## More notation

- $\kappa$ -smooth interpolant of  $g$ :

$$\mathcal{F}_\kappa(g) \equiv \{h \in \mathcal{C}[0, 1]^P : K(h) \leq \kappa \text{ and } h|_{\text{dom}(g)} = g\}.$$

$\mathcal{F}_\infty(f|_X)$  is the space of functions in  $\mathcal{C}[0, 1]^P$  that fit the data.

- *potential error of  $\hat{f} \in \mathcal{C}[0, 1]^P$  over the set of functions  $\mathcal{F}$ :*

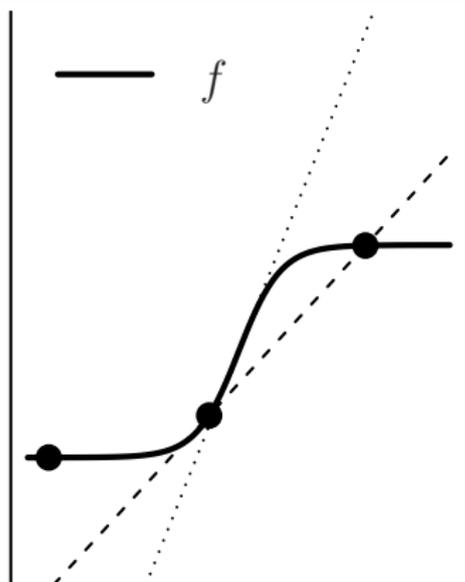
$$\mathcal{E}(w; \hat{f}, \mathcal{F}) \equiv \sup \left\{ |\hat{f}(w) - g(w)| : g \in \mathcal{F} \right\}.$$

- *maximum potential error of  $\hat{f} \in \mathcal{C}[0, 1]^P$  over the set of functions  $\mathcal{F}$ :*

$$\mathcal{E}(\hat{f}, \mathcal{F}) \equiv \sup_{w \in [0, 1]^P} \mathcal{E}(w; \hat{f}, \mathcal{F}) = \left\{ \|\hat{f} - g\|_\infty : g \in \mathcal{F} \right\}.$$

## Maximum potential error

- Example of *worst-case error* in IBC.
- “Real” uncertainty of  $\hat{f}$  is  $\mathcal{E}(\hat{f}, \mathcal{F}_\infty(f|_X))$ .
- Presumes  $f \in \mathcal{C}[0, 1]^p$ .
- Maximum potential error is infinite unless  $f$  has more regularity than mere continuity.
- If  $f \notin \mathcal{C}[0, 1]^p$ ,  $\hat{f}$  could differ from  $f$  by *more*.
- We lower-bound uncertainty of the *best possible* emulator of  $f$ , under optimistic assumption that  $K = K(f) = \hat{K} \equiv K(f|_X) \leq K(f)$



Dotted line is tangent to  $f$  where  $f$  attains its Lipschitz constant: slope  $K = K(f)$ . Dashed line is the steepest line that intersects any pair of observations: slope  $\hat{K} = K(f|_X) \leq K$ .

## More notation

- $\mathcal{F}_\kappa \equiv \mathcal{F}_\kappa(f|_X)$
- $\mathcal{E}_\kappa(\hat{f}) \equiv \mathcal{E}(\hat{f}, \mathcal{F}_\kappa)$
- *radius* of  $\mathcal{F} \subset \mathcal{C}[0, 1]^p$  is

$$r(\mathcal{F}) \equiv \frac{1}{2} \sup \{ \|g - h\|_\infty : g, h \in \mathcal{F} \}.$$

## First result

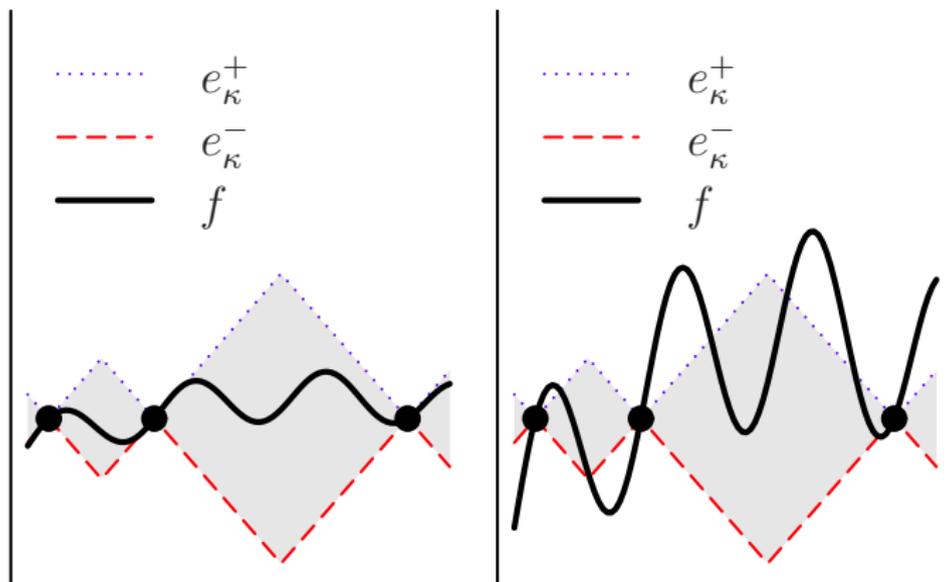
$$\mathcal{E}_\kappa(\hat{f}) \geq r(\mathcal{F}_\kappa). \quad (2)$$

Equality holds for the emulator that “splits the difference”:

$$f_\kappa^*(w) \equiv \frac{1}{2} \left[ \inf_{g \in \mathcal{F}_\kappa} g(w) + \sup_{g \in \mathcal{F}_\kappa} g(w) \right]$$

For all emulators  $\hat{f}$  that agree with  $f$  on  $X$ ,

$$\mathcal{E}_\kappa(\hat{f}) \geq \mathcal{E}_\kappa(\hat{f}_\kappa^*) \equiv \mathcal{E}_\kappa^*.$$



Left panel:  $\kappa = K$ . Right panel:  $\kappa < K$ .

If  $\kappa \geq K$  then  $e_{\kappa}^{-} \leq f \leq e_{\kappa}^{+}$ , so  $f \in \mathcal{F}_{\kappa}$ .

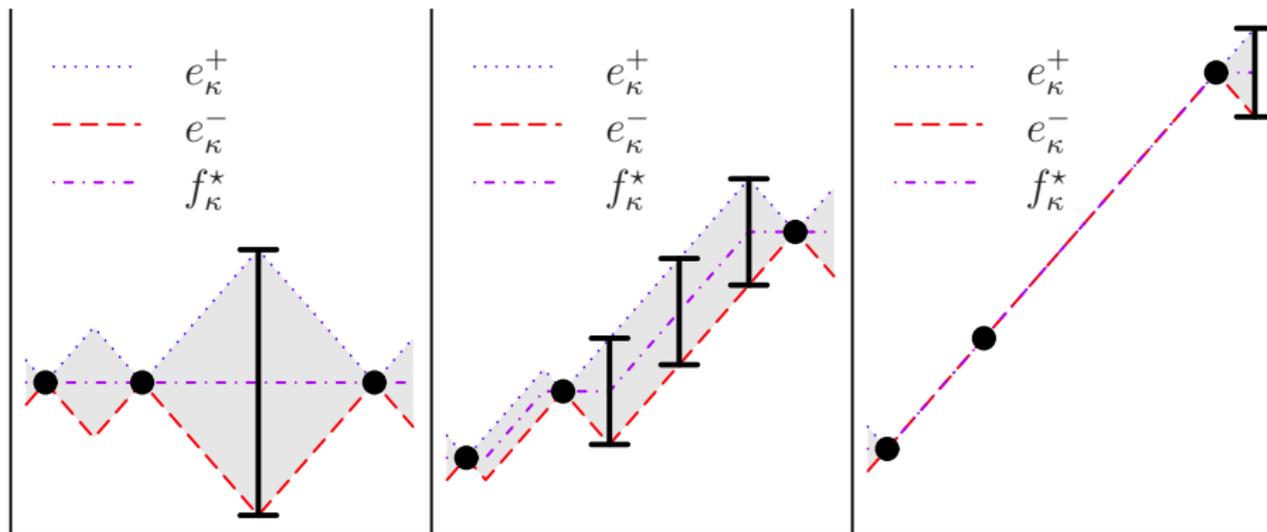
## Constructing $e^-$ , $e^+$ , and $e^*$

Define

- $e_{\kappa}^+(w) \equiv \min_{x \in X} [f(x) + \kappa d(x, w)]$
- $e_{\kappa}^-(w) \equiv \max_{x \in X} [f(x) - \kappa d(x, w)]$
- $e_{\kappa}^*(w) \equiv \frac{1}{2} [e_{f, X, \kappa}^+(w) - e_{f, X, \kappa}^-(w)]$

$e_{\kappa}^*(w)$  is minimax error at  $w$ :

smallest (across emulators  $\hat{f}$ ) maximum (across functions  $g$ ) error  
at the point  $w$



Black error bars are twice the maximum potential error over  $\mathcal{F}_{\kappa}$ .  
As the slope between observations approaches  $\kappa$ ,  $e^{*}(w)$  approaches 0 for points  $w$  between observations, and the maximum potential error over  $\mathcal{F}_{\kappa}$  decreases.

## Lower bounds on $n$

- Fix “tolerable error”  $\epsilon > 0$
- If  $\left\| \hat{f}|_A - g|_A \right\|_{\infty} \leq \epsilon$ , then  $\hat{f}$   $\epsilon$ -approximates  $g$  on  $A$ .  
If  $A = \text{dom}(g)$ , then  $\hat{f}$   $\epsilon$ -approximates  $g$ .
- If  $\mathcal{F}$  is a non-empty class of functions with common domain  $D$ , then  $\hat{f}$   $\epsilon$ -approximates  $\mathcal{F}$  on  $A \subset D$  if  $\forall g \in \mathcal{F}$ ,  $\hat{f}$   $\epsilon$ -approximates  $g$  on  $A$ .  
If  $A = D$ , then  $\hat{f}$   $\epsilon$ -approximates  $\mathcal{F}$ .

## $\epsilon$ -approximates and tolerable error

$\hat{f}$   $\epsilon$ -approximates  $\mathcal{F}$  if and only if the maximum potential error of  $\hat{f}$  on  $\mathcal{F}$  does not exceed  $\epsilon$ .

Since  $\hat{K}$  is the observed variation of  $f$  on  $X$ , a useful value of  $\epsilon$  would typically be much smaller than  $\hat{K}$ . (Otherwise, we might just as well take  $\hat{f}$  to be a constant.)

## Minimum potential computational burden

- For fixed  $\epsilon > 0$ , and  $Y \subset \text{dom}(f)$ ,  $Y$  is  $\epsilon$ -adequate for  $f$  on  $A$  if  $f_K^*$   $\epsilon$ -approximates  $\mathcal{F}_K(f|_Y)$  on  $A$ . If  $A = \text{dom}(f)$ , then  $Y$  is  $\epsilon$ -adequate for  $f$ .
- $B(x, \delta)$ : open ball in  $\mathbb{R}^p$  centered at  $x$  with radius  $\delta$ .
- $N_f \equiv \min\{\#Y : Y \text{ is } \epsilon\text{-adequate for } f\}$
- The *minimum potential computational burden* is

$$M \equiv \max\{N_g : g \in \mathcal{F}_K\}.$$

- Over all experimental designs  $Y$ ,  $M$  is the smallest number of data for which the maximum error of the best emulator based on those data is guaranteed not to exceed  $\epsilon$ .

## Upper bound on $N_f$

- For each  $x \in X$ ,  $f_K^*$   $\epsilon$ -approximates  $\mathcal{F}_K(f|_K)$  on (at least)  $B(x, \epsilon/K)$ .
- Thus,  $f_K^*$   $\epsilon$ -approximates  $\mathcal{F}_K$  on  $\bigcup_{x \in X} B(x, \epsilon/K)$ .
- Hence, the cardinality of any  $Y \subset [0, 1]^p$  for which

$$V \equiv \left\{ B\left(x, \frac{\epsilon}{K}\right) : x \in Y \right\} \supset [0, 1]^p$$

is an upper bound on  $N_f$ .

- In  $\ell_\infty$ ,  $[0, 1]^p$  can be covered by  $\lceil \frac{K}{2\epsilon} \rceil^p$  balls of radius  $\epsilon/K$ .

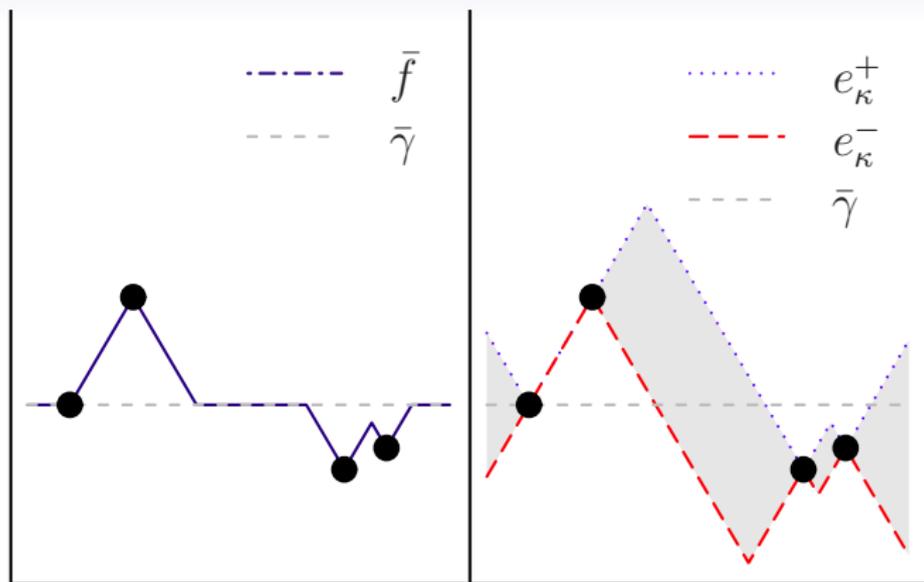
## Lower bound on $N_f$ : Heuristics

- Can happen that  $f_{\hat{K}}^*$   $\epsilon$ -approximates  $\mathcal{F}_K$  on regions of the domain not contained in  $\cup_{x \in X} B(x, \epsilon/K)$ .
- If  $f$  varies on  $X$ , then if  $g$  agrees with  $f$  at the data,  $g$  must vary too.
- Fitting the data “spends” some of  $g$ ’s Lipschitz constant: can’t get as far away from  $f$  as it could if  $f_X$  were constant.
- Can quantify to find lower bounds for  $M$ .

## Lower bound on $N_f$ : Construction

Define

- $\bar{\gamma} \equiv \arg \min_{\gamma \in \mathbb{R}} \sum_{x \in X} |f(x) - \gamma|^p.$
- $X^+ \equiv \{x \in X : f(x) \geq \bar{\gamma}\}$
- $X^- \equiv \{x \in X : f(x) < \bar{\gamma}\}.$
- $Q_+ \equiv \bigcup_{x \in X^+} \left\{ B \left( x, \frac{f(x) - \bar{\gamma}}{\hat{K}} \right) \cap [0, 1]^p \right\}$
- $Q_- \equiv \bigcup_{x \in X^-} \left\{ B \left( x, \frac{\bar{\gamma} - f(x)}{\hat{K}} \right) \cap [0, 1]^p \right\}$
- $\bar{Q} \equiv [0, 1]^p \setminus (Q_+ \cup Q_-).$
- $\bar{f}(w) \equiv \{e_{\hat{K}}^-(w), w \in Q_+; e_{\hat{K}}^+(w), w \in Q_-; \bar{\gamma}, w \in \bar{Q}\}.$



$\bar{f}$  (left panel) is comprised of segments of  $e_{\hat{K}}^+$ ,  $e_{\hat{K}}^-$  and the constant  $\bar{\gamma}$  (right panel).  $\bar{f}$  constant over roughly half of the domain. No function between  $e_{\hat{K}}^-$  and  $e_{\hat{K}}^+$  (inclusive) is constant over a larger fraction of the domain.

## Potential computational burden: bounds for Lebesgue measure

- $\mu$ : Lebesgue measure.

$$\mu(\bar{Q}) \geq 1 - \sum_{x \in X} \mu \left( B \left( x, |f(x) - \bar{\gamma}| / \hat{K} \right) \right).$$

- $C_2 \equiv \frac{\pi^{p/2}}{\Gamma(p/2+1)}$  and  $C_\infty \equiv 2^p$ .
- For  $q \in \{2, \infty\}$ ,

$$\mu(\bar{Q}) \geq 1 - C_q \sum_{x \in X} \left( |f(x) - \bar{\gamma}| / \hat{K} \right)^p.$$

- $M \geq \left\lceil \frac{\mu(\bar{Q})}{\mu(B(0, \epsilon / \hat{K}))} \right\rceil \geq \left\lceil \epsilon^{-p} \left[ \frac{\hat{K}^p}{C_q} - \sum_{x \in X} |f(x) - \bar{\gamma}|^p \right] \right\rceil$

## Uncertainty Quantification Strategic Initiative–LLNL

- Uncertainty Quantification Strategic Initiative at LLNL: 1154 climate simulations using the Community Atmosphere Model (CAM).
- $p = 21$  parameters scaled so that  $[0, 1]$  has all plausible values.
- $f$  is global average upwelling longwave flux (FLUT) approximately 50 years in the future.
- Each run took several days on a supercomputer.
- Several approaches to choose  $X \subset [0, 1]^p$ : Latin hypercube, one-at-a-time, and random-walk multiple-one-at-a-time.
- 1154 simulations total.

## CAM calculations

- $\bar{\gamma} = 232.77$
- For  $q = 2$ ,  $\hat{K} = 14.20$ :  

$$M \geq \left[ \epsilon^{-21} \left[ \frac{1.57 \times 10^{24}}{0.0038} - 6.81 \times 10^{24} \right] \right] > \epsilon^{-21} \times 10^{26}$$

If  $\epsilon$  is 1% of  $\hat{K}$ , then  $M \geq 10^{43}$ .  
 Even if  $\epsilon$  is 50% of  $\hat{K}$ ,  $M > 10^8$ .
- For  $q = \infty$ ,  $\hat{K} = 34.68$ :  

$$M \geq \left[ \epsilon^{-21} \left[ \frac{2.19 \times 10^{32}}{2^{21}} - 6.81 \times 10^{25} \right] \right] > \epsilon^{-21} \times 10^{25}$$

## Universal bound from the data

### Theorem

$$\mathcal{E}_K(\hat{f}) \geq \sup e_{\hat{K}}^*.$$

$\sup e_{\hat{K}}^*$ , a statistic calculable from data  $f|_X$ , is a lower bound on the maximum potential error for *any* emulator  $\hat{f}$  based on the observations  $f|_X$ .

## More isn't necessarily better

### Theorem

If  $\sup e_{\hat{K}}^* \geq \hat{K}/2$ , then

$$\mathcal{E}_K(\hat{f}) = \mathcal{E}_K(\hat{f}, \mathcal{F}_K(f|_X)) \geq \frac{K}{2} \geq \mathcal{E}_K(\hat{g}, \mathcal{F}_K(f|_{\{z\}})).$$

If  $\sup e_{\hat{K}}^* \geq \hat{K}/2$ , no  $\hat{f}$  based on  $f|_X$  has smaller maximum potential error than the constant emulator based on one observation at the centroid  $z$  of  $[0, 1]^p$

## Implications for CAM

- $\sup e_{\hat{K}}^* = 20.95 \geq 17.34 = \hat{K}/2$
- Hence,  $\mathcal{E}_K(\hat{f}) \geq K/2$  for every emulator  $\hat{f}$ .
- Maximum potential error would have been no greater had we just observed  $f$  at  $z$  and emulated by  $\hat{f}(w) = f(z)$  for all  $w \in [0, 1]^p$ .

## Extensions

- Covered maximum uncertainty over all  $w \in [0, 1]^P$ : crucial for some applications.
- In others, maybe interesting to know fraction of  $[0, 1]^P$  where uncertainty is large.
- Can estimate the fraction of  $[0, 1]^P$  for which  $e^* \geq \epsilon > 0$  by sampling.
- Draw points  $w \in [0, 1]^P$  at random; evaluate  $e^*$  at each  $w$ .
- Yields binomial lower confidence bounds for the fraction of  $[0, 1]^P$  where uncertainty is large, and confidence bounds for quantiles of the potential error.
- Another issue: take  $\epsilon$  as fraction of “typical value” rather than fraction of  $K$  or  $\hat{K}$
- But why? Not same as estimating  $\bar{f}$ , which is easier.

## CAM: bounds on percentiles of error

norm	units	95% lower confidence bound			
		lower quartile	median	upper quartile	average
Euclidean	$\hat{K}/2$	1.462	1.599	1.732	1.599
supremum	$\hat{K}/2$	0.648	0.716	0.781	0.715
Euclidean	$\hat{\gamma}$	0.044	0.049	0.053	0.049
supremum	$\hat{\gamma}$	0.048	0.053	0.058	0.053

Error of minimax emulator  $f_{\hat{K}}^*$  of CAM model from 1154 LLNL observations. Col 1: metric  $d$  used to define  $K$ . Cols 3–5: binomial lower confidence bounds for quartiles of the pointwise error, obtained by inverting binomial tests.

Col 6: 95% lower confidence bound for integral of the pointwise error over  $[0, 1]^P$ , based on inverting a z-test.

Cols 3–6 are expressed as a fraction of the quantity in col 2. Based on 10,000 random samples.

## Computational Burden for “typical value”

norm	$\epsilon$	lower bound on $M$
Euclidean	$0.02\hat{\gamma}$	$3.6 \times 10^{12}$
	$0.04\hat{\gamma}$	1,720,354
	$0.06\hat{\gamma}$	345
	$0.08\hat{\gamma}$	1
supremum	$0.02\hat{\gamma}$	$8.6 \times 10^{10}$
	$0.04\hat{\gamma}$	413,595
	$0.06\hat{\gamma}$	83
	$0.08\hat{\gamma}$	1

## Conclusions

- In some problems, every emulator based on any tractable number of observations of  $f$  has large maximum potential error (and the potential error is large over much of the domain), even if  $f$  is no less regular than it is observed to be.
- Can find sufficient conditions under which all emulators are potentially substantially incorrect.
- Conditions depend only on the observed values of  $f$ ; can be computed from the same observations used to train an emulator, at small incremental cost.
- Conditions are sufficient but not necessary:  $f$  could be less regular than any finite set of observations reveals it to be.
- It is not possible to give necessary conditions that depend only on the data.
- Conditions seem to hold for problems with large societal interest.

## Directions

- Reducing the potential error in HEB problems requires more information about  $f$  (knowledge, not assumptions), or changing the measure of uncertainty—changing the question.
- Both tactics are application-specific: the science dictates the conditions that actually hold for  $f$  and the senses in which it is useful to approximate  $f$ .
- Not clear that simulation and emulators help address the most important questions.
- Approximating  $f$  pointwise rarely ultimate goal; most properties of  $f$  are nuisance parameters.
- Important questions about  $f$  might be answered more directly.
- Heroic simulations and emulators may be distractions.